

Conceptual Design for SR/SP

Topics:

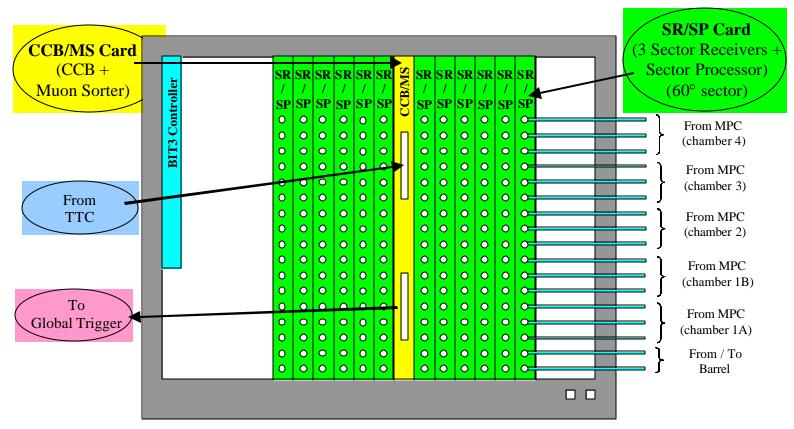
- Board Layout
- Bit counts and data serialization
- Memory architecture
- → SP-in-a-chip
- Backplane
- DAQ interface
- → Manpower
- Software limitations





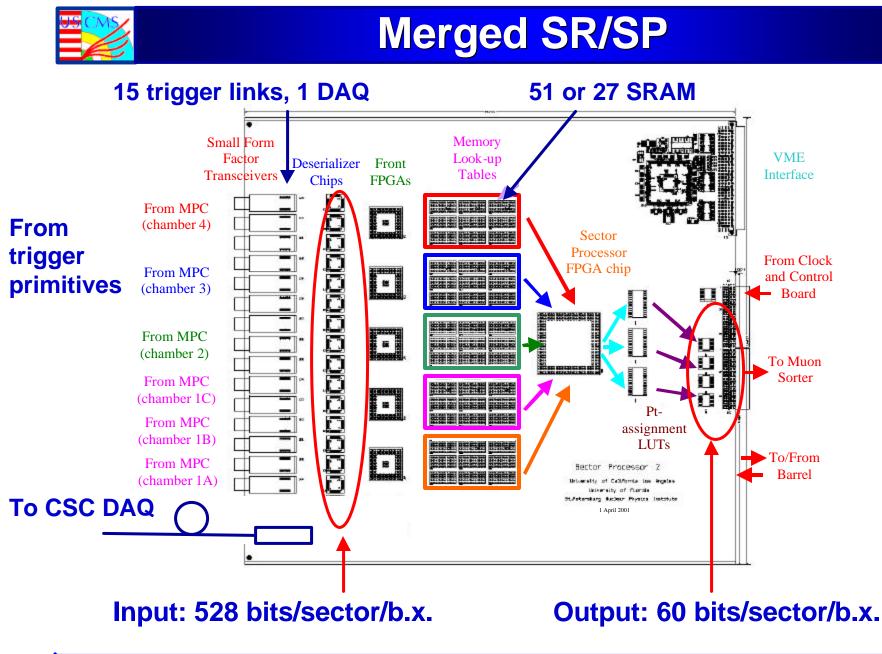
Possible Single Crate Solution

Track-Finder crate (1.6 Gbits/s optical links)



- Total latency: ~ 20Bx (from input of SR/SP card to output of CCB/MS card)
- Power consumption: ~ 500W per crate
- 15 ptical connections per SR/SP card
- Custom backplane for SR/SPs <> CCB/MS connection









Bi-Directional Optical Links

Since we have both transmitters and receivers in the optical connection, this allows the option to send data as well as receive

Makes testing much easier (1 board sends data to other)



SR/SP Inputs



Sent on
first
frame

Signal	Bits / stub	Bits / 3 stubs (1 MPC)	Bits / 15 stubs (ME1–ME4)	Description	
¹ / ₂ Strip *	8	24	120	¹ / ₂ strip label	Deduced
CLCT	4	12	75	Pattern number without	Reduced
pattern *				4/6, 5/6, 6/6	from 5
L/R bend *	1	3	15	Sign bit for pattern	
Quality *	3	9	45	Computed by TMB	
Wire group	7	21	105	Wire group label	
Accelerator m	1	3	15	Straight wire pattern	
CSC i.d.	4	12	60	Chamber label in subsector	
BXN	2	6	30	2 LSB of BXN	
Valid pattern	1	3	15	Must be set for above to apply	
Spare	1	3	15		— Added
Total:	32	96	480	(240 bits at 80 MHz)	

→DT Track-Finder delivers 2 track stubs each BX via LVDS

Signal	Bits / stub	Bits / 2 stubs (MB1: 60°)	Description
f	12	24	Azimuth coordinate
\mathbf{f}_{b}	5	10	<pre>\$ bend angle</pre>
Quality	3	6	Computed by TMB
BXN	2	4	2 LSB of BXN
Synch/Calib	1	2	DT Special Mode
Muon Flag	1	2	2 nd muon of previous BX
Total:	24	48	

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SR/SP Outputs

→ 6 track stubs are delivered to DT Track-Finder each BX via LVDS (can we multiplex at 80 MHz to save connector space?)

Signal	Bits / stub	Bits / 2 stubs (ME1: 20°)	Bits / 6 stubs (ME1: 60°)	Bits / 6 stubs @ 80 MHz	Description
f	12	24	72	36	Azimuth coordinate
h	1	2	6	3	DT/CSC region flag
Quality	3	6	18	9	Computed by TMB
BXN	—	2	6	3	2 LSB of BXN
	16	34	102	51	Total

→ 3 muons per SP are delivered to Muon Sorter via GTLP backplane

	Signal	Bits / m	Bits / 3 m (1 SP)	Bits / 36 m (12 SP)	Description	
	f	5	15	180	Azimuth coordinate	
	h	5	15	180	Pseudorapidity	
Sent on	Rank *	7	21	252	5 bits $p_{\rm T}$ + 2 bits quality	
	Sign *	1	3	36]
first {	BXN *	—	2	24	2 LSB of BXN	Added,
frame	Error *	_	1	12		· · · · · · · · · · · · · · · · · · ·
liano (Spare *	1	3	12		← quality?
	Total:	19	60	720	(360 bits at 80 MHz)	





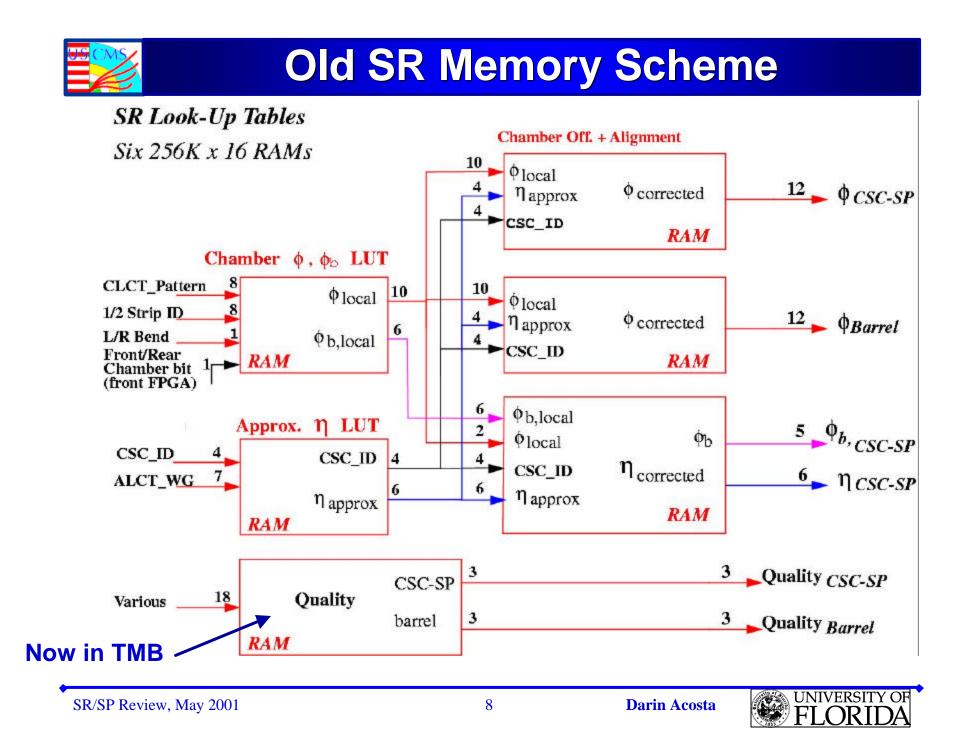
SR/SP Internal Dataflow

→ Data delivered from SR to SP

	Signal	Bits / stub	Bits / 6 stubs (ME1)	Bits / 15 stubs (ME1–ME4)	Description
	f	12	72	180	Azimuth coordinate
	\mathbf{f}_{b}	5	30	75	ϕ bend angle
	h	6	36	90	Pseudorapidity
ME1 {	Accelerator m	1	6	15	η bend angle
	Front/Rear *	1	6	6	ME1 chamber stagger
	CSC ghost *	_	4	4	2 stubs in same ME1 CSC
	Quality	3	18	45	Computed by TMB
	Total:	28	172	415	(sent at 80 MHz)

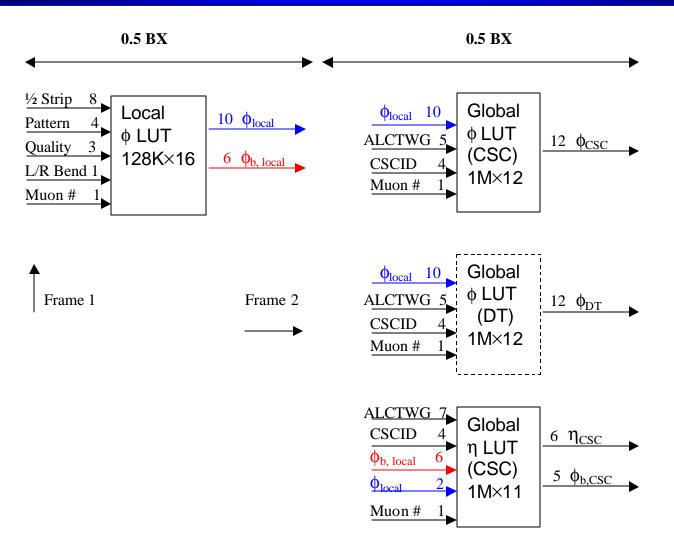
226 if stubs multiplexed







New SR Memory Scheme







Discussion of SR Memory (1)

Data Frames:

- → Data arrives off links @ 80 MHz
- The proposed framing scheme implies no latency loss
 - First LUT operates on first frame only (but must reduce CLCT pattern label by 1 bit)
 - Can send 2 muons through one memory set with only 0.5 BX latency penalty to reduce chip count
- This frame definition must be applied in the TMB where the data is generated and first serialized (i.e. before MPC) to avoid latency penalty

Memories:

- → LUT for DT only applies to ME1
- → Chip count is 4 or 3 per stub, down from 6 originally
- Increased memory size to 1M (okay for synch. SRAM)
- "Muon #" only applies if more than one stub in a BX is sent through same memory



Discussion of SR Memory (2)

One memory set per stub:

- → 6⁴ + 9³ = 51 chips
- J BX latency
- → 415 signals to SP

Multiplex stubs at 80 MHz:

- → 3⁴ + 5³ = 27 chips
- → 1.5 BX latency
- → 226 signals to SP

First SR had 36 chips and 1 BX latency

Memory choices:

- Current synch SRAM clocked at 160 MHz (tested)
- next generation synch SRAM clocked at 80 MHz
- asynch SRAM (but must remove 2 bits in final LUTs)





Pipelined Memory Tests

Developed small evaluation board to test two pipelined memories in series

- Samsung 1M x 18 synch. SRAM (K7A161800M)
- Include scheme to multiplex two muon stubs through same memory set @ 80 MHz
- Tested chips up to 150 MHz and encountered no errors with random number inputs
 - Specified maximum frequency is 180 MHz

Low power

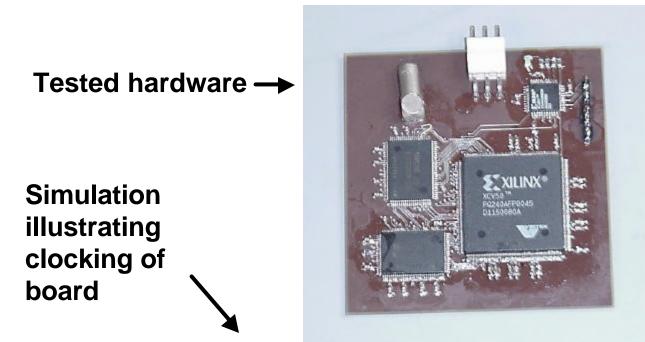
- → ~1W per memory at 150 MHz
- Latency determination
 - → 2 clocks per memory (4 clocks for two in series)
 - Next generation will require just one clock

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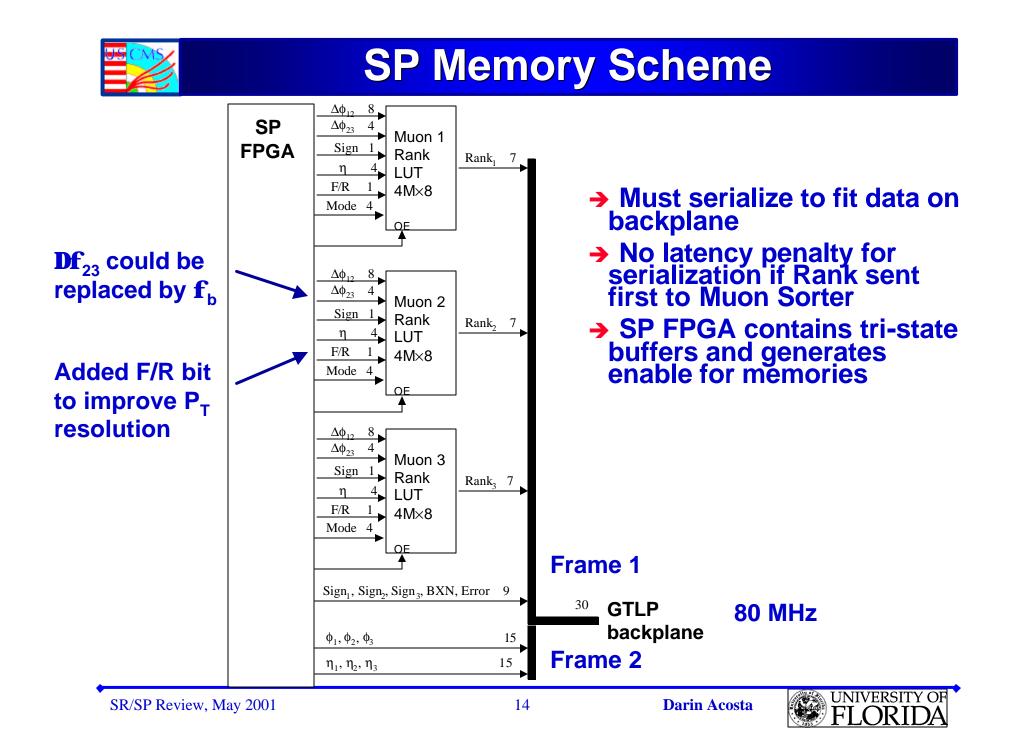




SR Memory Prototype



😸 Logic Simulator - Xilinx Foundation F3.1i [time_sim] - [Waveform	n Yiewer 0]			<u>- 0 ×</u>
Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Window He Image: Signal Waveform Device Options Tools View Waveform Tools View View Waveform Tools View Wav	elp Break - Andreak - And	1		<u>_6×</u>
1ns/div 11340ns 350ns 360ns 337ns 11 11 11 11 11 11 11 11 11 11 11 11 11	370ns 380ns 390ns 400ns	410ns 420ns 430ns 440ns	: 450ns 460ns 470ns	5 480ns 490ns
	CD45 X3926B 245B X048B6 XX3122D XX3CD45 X2245B X3 XX3CD45 X2245B	X33516 X26A2C X0916C X122D8 X39A8B X048B6 X33516 X0 R6A2 X3122D X30D43 X2249 X186A2 X3122D X3122D X186A2	1916C ((26A2C)(122D8	X1ABB1 A X02B61 X00D458 XX X38516 X39A8B X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X048B6 X0500ns
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SP in a Chip Study

Feasibility study was performed to fit all Sector Processor logic into one FPGA

- Merged all separate schematics from current SP prototype into one project (17 FPGAs)
- Transformed large Track Assembler LUTs into a Verilog algorithm for FPGA
- → Utilized 63% of the resources of a Xilinx Virtex-E (XCV1600EFG680-8)

\square Must understand how much \mathbf{f}_{b} logic adds

Simulation shows that the latency of the SP logic is 11 BX at a maximum frequency of 41 MHz

□ Add 1 BX for final P_T Assignment LUT

□ Compare to 15 BX of current SP prototype **▶** save 3 BX

- ChannelLink between SR and SP removed (save 4 BX more)
- → SP Chip I/O:

415 (or 226) CSC + 48 DT input bits

 \Rightarrow ~600 max I/O

~135 output bits + control signals





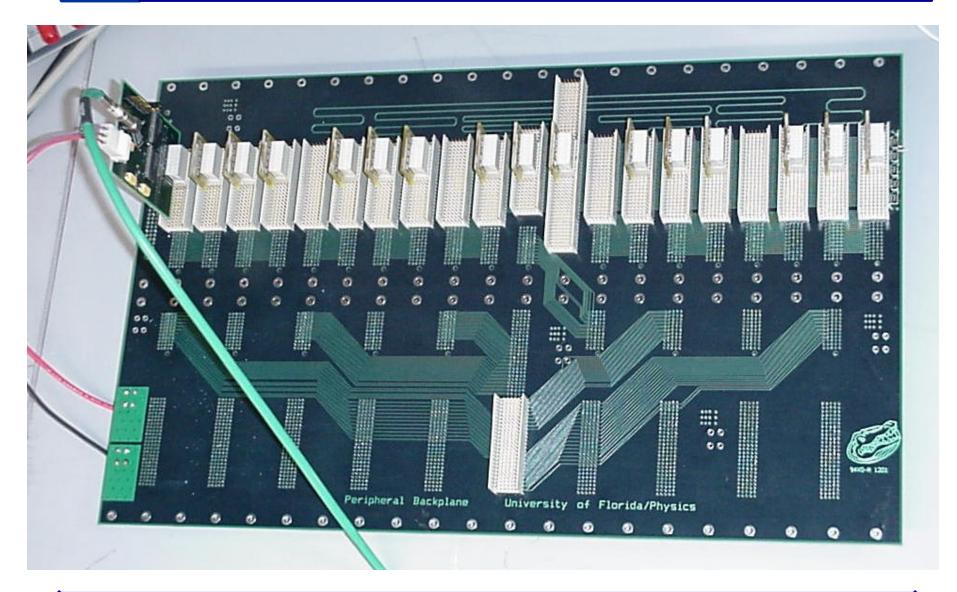
Backplane Development

Next generation backplane technology will be GTLP

- No differential signals (fewer traces)
- We first tested a small prototype backplane with GTLP signals
 It works: tested drivers from Fairchild, and Xilinx Virtex I/O
- We have now tested a full 21 slot custom VME backplane for use in the CSC front-end peripheral crate
 - □ Includes 40 MHz bussed signals and 80 MHz point-to-point
 - Highest density is ~660 signals into Muon Port Card (vs. ~720 signals into CSC Muon Sorter in CSC TF crate) multiplexed at 80 MHz
 - \blacksquare Have tested bussed signals with backplane fully loaded \blacktriangleright



Prototype Peripheral Crate Backplane



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CSC TF DAQ Bandwidth

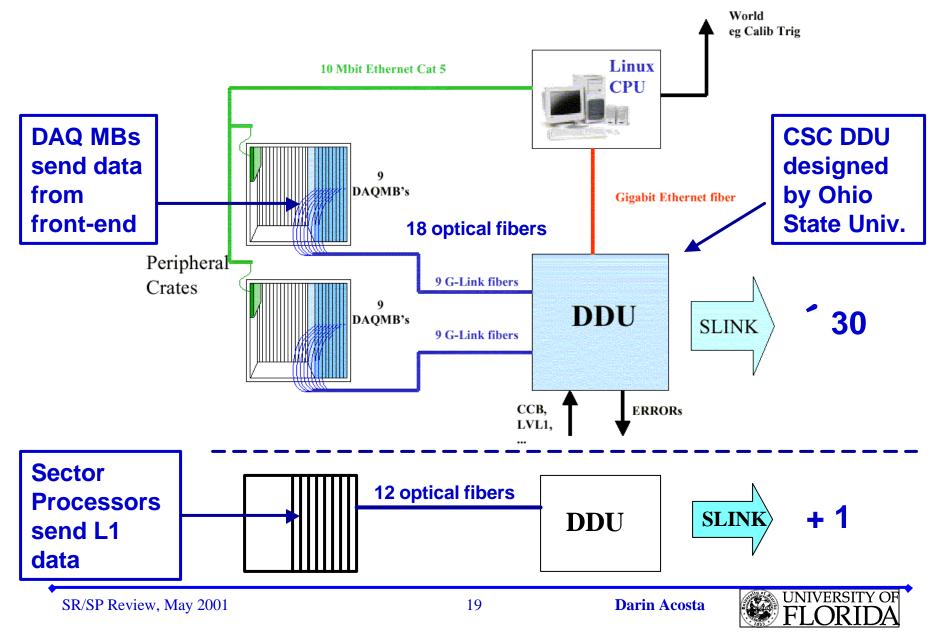
Send input of SR and output of SP to DAQ stream for diagnostics

- → Send ~600 bits (80B) per L1A per SR/SP
- → 12 SR/SP send 1kB per L1A
- → 100 kHz L1A rate ₽ 100 MB/s
- → One S-LINK64 handles 200 MB/s
- → Note that trigger data is expected to be sparse, so this bandwidth is an upper limit and should be compressed
- SC Track-Finder DAQ acts as additional DDU for CSC system (plan to use existing DDU design by OSU)
 - OSU may use new HP serializer in place of TI for compatibility with Gbit ethernet
 - They should have results from an evaluation board within a month





Mirror CSC DAQ Path





Manpower

University of Florida

- → D.A. PI
- → Alex Madorsky lead engineer
- Bobby Scurlock graduate student
 - **Trigger simulations**
 - **B** SP firmware/software tuning, crate tests

PNPI

- → Victor Golovtsov PI
- → Lev Uvarov design engineer
 - Replaces Boris

Extensive experience on D0 (muon readout), E781, E761

- UCLA
 - → R.C. PI
 - Jason Mumford graduate student
 - Slava postdoc
 - Both maintain trigger primitive and SR software





Software Limitations

CLCT patterns and pattern number

- → No f_b from SR
- $\rightarrow \mathbf{f}_{b}$ not used for extrapolation in SP
 - Might reduce backgrounds
 - Logic size not counted in SP chip study
- \rightarrow **f**_b could improve P_T assignment
- → Improved f precision results from using 6 layers vs. 1
 - □ Could improve P_T resolution
- **Track-Finder algorithms**
 - Bunch Crossing Analyzer not implemented or tested
 - New Verilog Track Assembler needs simulation
 - → Miscellaneous cuts need tuning: h, quality,...
 - Should improve low P_T rejection
- Validation against current HW designs
 - Need closer link to hardware LUTs and algorithms
 - Improve maintenance of design to shorten debug time for next prototypes





Design Maintenance

Will overhaul some of the SP software/firmware to facilitate changes to both

- Have SW algorithms match Verilog better
- Have SW read same HW LUTs (it already generates them)

Plan to test next SP design even before construction!

- Add utilities to write ORCA data into Xilinx simulator format and to compare simulator output to ORCA
- → Gives us a head start on validating logic design
- Will allow us to focus on HW debugging rather than SW debugging when testing the next prototype

